

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

# **PRODUCT/PROCESS CHANGE NOTICE (PCN)**

	04.02	DATE	( M 2010					
		DATE:	6-May-2019				ANGED DEVICES:	
Product Affected				Produc				
	F2913NLGK8			Back N			the test location is	
				Date C	Code	•	IDT and available on	
				• Other		request		
Date Effective:	6-Aug-2019							
Contact:	IDT PCN DESK			Attachmen	nt:	Yes	D No	
E-mail:	pcndesk@idt.com			Samples:	Please cont sample requ		les representative for	
DESCRIPTION	AND PURPOSE OF CI	HANGE:						
Die Technolog	gy							
□ Wafer Fabrica	afer Fabrication Process This notification is to advise our customers that IDT is adding Sigurd, Taiwan as an							
				Fest process for the selective products that are presently tested in				
□ Equipment IDT Penang, Malays			nang, Malaysia	1 1 2				
□ Material								
Testing Attachment I details the change.								
Manufacturing	g Site							
Data Sheet								
□ Other								
<b>RELIABILITY/QUALIFICATION SUMMARY:</b> There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.								
CUSTOMER A	CKNOWLEDGMENT	OF REC	EIPT:					
CUSTOMER ACKNOWLEDGMENT OF RECEIPT:								
IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice								
to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.								
	right to ship either version		ctured after the	process cha	ange effectiv	e date until the i	nventorv	
	rsion has been depleted.	, in interior		process end	inge enteent		ii ( ciitoi y	
on the carner ver	Ision has been depicted.							
Customer:			_	] Appro	oval for sh	hipments prio	r to effective date.	
Name/Date:			E-	-Mail Addr	ess:			
Title:			Phone# /Fax# :					
CUSTOMER COMMENTS:								
IDT ACKNOW	LEDGMENT OF RECH	ПЬТ∙						
RECD. BY:				DATE:				



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#### ATTACHMENT I - PCN # : TB1904-03

PCN Type:Manufacturing Site - Alternate Test LocationData Sheet Change:None

**Detail Of Change:** 

This notification is to advise our customers that IDT is adding Sigurd, Taiwan as an alternate facility for Test process for the selective products that are presently tested in IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facilities and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards are the same at the qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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### ATTACHMENT I - PCN # : TB1904-03

#### Qualification Information and Qualification Data: <u>Electrical Test Correlation Results</u>

Vehicle:F2913Sample size:10 good and 5 reject units; 10 loop test correlation

Description	Existing Test (IDT, Penang)	Alternate Test (Sigurd, Taiwan)	
Tester Platform	J750	UltraFlex	
Test Program	F2913_FT_rev0.4	F2913_UFlex_v1	
Test Site	Dual Site	Octal Site	
Test Temperature	Ambient	Ambient	
Test Correlation Results	100%	100%	
Number of Good Units	10 pcs	10 pcs	
10 good units datalog correlation	Passed	Passed	
Number of Loop Test	10	10	
10 good units datalog correlation	Passed	Passed	
Number of Reject Units	5 pcs	5 pcs	
5 reject units datalog correlation	Passed	Passed	